AMD Xilinx - XC3S200AN-5FTG256C Datasheet

Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	448
Number of Logic Elements/Cells	4032
Total RAM Bits	294912
Number of I/O	195
Number of Gates	200000
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-LBGA
Supplier Device Package	256-FTBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc3s200an-5ftg256c

Notice of Disclaimer

Spartan-3AN FPGA Design Documentation

The functionality of the Spartan®-3AN FPGA family is described in the following documents. The topics covered in each guide are listed below:

- **DS706: Extended Spartan-3A Family Overview**
- **UG331: Spartan-3 Generation FPGA User Guide**
  - Clocking Resources
  - Digital Clock Managers (DCMs)
  - Block RAM
  - Configurable Logic Blocks (CLBs)
    - Distributed RAM
    - SRL16 Shift Registers
    - Carry and Arithmetic Logic
  - I/O Resources
  - Embedded Multiplier Blocks
  - Programmable Interconnect
  - ISE® Design Tools
  - IP Cores
  - Embedded Processing and Control Solutions
  - Pin Types and Package Overview
  - Package Drawings
  - Powering FPGAs
  - Power Management
- **UG332: Spartan-3 Generation Configuration User Guide**
  - Configuration Overview
    - Configuration Pins and Behavior
    - Bitstream Sizes
  - Detailed Descriptions by Mode
    - Master Serial Mode using Xilinx® Platform Flash
    - Master SPI Mode using SPI Serial Flash PROM
    - Internal Master SPI Mode
    - Master BPI Mode using Parallel NOR Flash
    - Slave Parallel (SelectMAP) using a Processor
    - Slave Serial using a Processor
    - JTAG Mode
  - ISE iMPACT Programming Examples
  - MultiBoot Reconfiguration
  - Design Authentication using Device DNA
- **UG333: Spartan-3AN FPGA In-System Flash User Guide**
  - For FPGA applications that write to or read from the In-System Flash memory after configuration
  - SPI_ACCESS interface
  - In-System Flash memory architecture
  - Read, program, and erase commands
  - Status registers
  - Sector Protection and Sector Lockdown features
  - Security Register with Unique Identifier

Create a Xilinx user account and sign up to receive automatic e-mail notification whenever this data sheet or the associated user guides are updated.

- **Sign Up for Alerts on Xilinx.com**
  https://secure.xilinx.com/webreg/register.do?group=myprofile&languageID=1

Spartan-3AN FPGA Starter Kit

For specific hardware examples, please see the Spartan-3AN FPGA Starter Kit board web page, which has links to various design examples and the user guide.

- **Spartan-3AN FPGA Starter Kit Board Page**
  http://www.xilinx.com/s3anstarter
- **UG334: Spartan-3AN FPGA Starter Kit User Guide**

Related Product Families

The Spartan-3AN FPGA family is generally compatible with the Spartan-3A FPGA family.

- **DS529: Spartan-3A FPGA Family Data Sheet**

Revision History

The following table shows the revision history for this document.

Date	Version	Revision
02/26/07	1.0	Initial release.
08/16/07	2.0	Updated for Production release of initial device.
09/12/07	2.0.1	Minor updates to text.
09/24/07	2.1	Added note that In-System Flash commands were not supported by simulation until ISE 10.1 software.
12/12/07	3.0	Updated to Production status with Production release of final family member, XC3S50AN. Noted that SPI_ACCESS simulation is supported in ISE 10.1 software. Updated links.
06/02/08	3.1	Minor updates.
11/19/09	3.2	In the Spartan-3AN FPGA Design Documentation section, added link to DS706, *Extended Spartan-3A Family Overview* and removed references to older software versions.
12/02/10	4.0	Updated link to sign up for Alerts and updated Notice of Disclaimer.
04/01/11	4.1	Added the FT(G)256 package selection for the XC3S50AN and XC3S400AN devices and the FG(G)484 package selection for the XC3S1400AN device throughout this data sheet.

Notice of Disclaimer

DC Electrical Characteristics

In this section, specifications can be designated as Advance, Preliminary, or Production. These terms are defined as follows:

Advance: Initial estimates are based on simulation, early characterization, and/or extrapolation from the characteristics of other families. Values are subject to change. Use as estimates, not for production.

Preliminary: Based on characterization. Further changes are not expected.

Production: These specifications are approved once the silicon has been characterized over numerous production lots. Parameter values are considered stable with no future changes expected.

All parameter limits are representative of worst-case supply voltage and junction temperature conditions. **Unless otherwise noted, the published parameter values apply to all Spartan®-3AN devices. AC and DC characteristics are specified using the same numbers for both commercial and industrial grades.**

Absolute Maximum Ratings

Stresses beyond those listed under Table 6: Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only; functional operation of the device at these or any other conditions beyond those listed under the Recommended Operating Conditions is not implied. Exposure to absolute maximum conditions for extended periods of time adversely affects device reliability.

Table 6: **Absolute Maximum Ratings**

Symbol	Description	Conditions	Min	Max	Units
V_{CCINT}	Internal supply voltage		–0.5	1.32	V
V_{CCAUX}	Auxiliary supply voltage		–0.5	3.75	V
V_{CCO}	Output driver supply voltage		–0.5	3.75	V
V_{REF}	Input reference voltage		–0.5	V_{CCO} + 0.5	V
V_{IN}	Voltage applied to all User I/O pins and dual-purpose pins	Driver in a high-impedance state	–0.95	4.6	V
	Voltage applied to all Dedicated pins		–0.5	4.6	V
I_{IK}	Input clamp current per I/O pin	$-0.5V < V_{IN} < (V_{CCO} + 0.5V)$(1)	–	±100	mA
V_{ESD}	Electrostatic Discharge Voltage	Human body model	–	±2000	V
		Charged device model	–	±500	V
		Machine model	–	±200	V
T_J	Junction temperature		–	125	°C
T_{STG}	Storage temperature		–65	150	°C

Notes:

1. Upper clamp applies only when using PCI IOSTANDARDs.
1. For soldering guidelines, see UG112: Device Package User Guide and XAPP427: Implementation and Solder Reflow Guidelines for Pb-Free Packages.

Device DNA Read Endurance

Table 17: **Device DNA Identifier Memory Characteristics**

Symbol	Description	Minimum	Units
DNA_CYCLES	Number of READ operations or JTAG ISC_DNA read operations. Unaffected by HOLD or SHIFT operations	30,000,000	Read cycles

In-System Flash Memory Data Retention, Program/Write Endurance

Table 18: **In-System Flash (ISF) Memory Characteristics**

Symbol	Description	Minimum[(1)]	Units
ISF_RETENTION	Data retention	20	Years
ISF_ACTIVE	Time that the ISF memory is selected and active. SPI_ACCESS design primitive pins CSB = Low, CLK toggling	2	Years
ISF_PAGE_CYCLES	Number of program/erase cycles, per ISF memory page	100,000	Cycles
ISF_PAGE_REWRITE	Number of cumulative random (non-sequential) page erase/program operations within a sector before pages must be rewritten	10,000	Cycles
ISF_SPR_CYCLES	Number of program/erase cycles for Sector Protection Register	10,000	Cycles
ISF_SEC_CYCLES	Number of program cycles for Sector Lockdown Register per sector, user-programmable field in Security Register, and Power-of-2 Page Size	1	Cycle

Notes:

1. Minimum value at which functionality is still guaranteed. Do not exceed these values.

Switching Characteristics

All Spartan-3AN FPGAs ship in two speed grades: -4 and the higher performance -5. Switching characteristics in this document are designated as Preview, Advance, Preliminary, or Production, as shown in Table 19. Each category is defined as follows:

Preview: These specifications are based on estimates only and should not be used for timing analysis.

Advance: These specifications are based on simulations only and are typically available soon after establishing FPGA specifications. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary: These specifications are based on complete early silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting preliminary delays is greatly reduced compared to Advance data.

Production: These specifications are approved once enough production silicon of a particular device family member has been characterized to provide full correlation between speed files and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

Software Version Requirements

Production-quality systems must use FPGA designs compiled using a speed file designated as PRODUCTION status. FPGA designs using a less mature speed file designation should only be used during system prototyping or pre-production qualification. FPGA designs with speed files designated as Preview, Advance, or Preliminary should not be used in a production-quality system.

Whenever a speed file designation changes, as a device matures toward Production status, rerun the latest Xilinx® ISE® software on the FPGA design to ensure that the FPGA design incorporates the latest timing information and software updates.

In some cases, a particular family member (and speed grade) is released to Production at a different time than when the speed file is released with the Production label. Any labeling discrepancies are corrected in subsequent speed file releases. See Table 19 for devices that can be considered to have the Production label.

All parameter limits are representative of worst-case supply voltage and junction temperature conditions. **Unless otherwise noted, the published parameter values apply to all Spartan-3AN devices. AC and DC characteristics are specified using the same numbers for both commercial and industrial grades.**

Create a Xilinx user account and sign up to receive automatic e-mail notification whenever this data sheet or the associated user guides are updated.

• Sign Up for Alerts

https://secure.xilinx.com/webreg/register.do?group=myprofile&languageID=1

Timing parameters and their representative values are selected for inclusion either because they are important as general design requirements or they indicate fundamental device performance characteristics. The Spartan-3AN speed files (v1.41), part of the Xilinx Development Software, are the original source for many but not all of the values. The speed grade designations for these files are shown in Table 19. For more complete, more precise, and worst-case data, use the values reported by the Xilinx static timing analyzer (TRACE in the Xilinx development software) and back-annotated to the simulation netlist.

Table 19: **Spartan-3AN Family v1.41 Speed Grade Designations**

Device	Preview	Advance	Preliminary	Production
XC3S50AN				-4, -5
XC3S200AN				-4, -5
XC3S400AN				-4, -5
XC3S700AN				-4, -5
XC3S1400AN				-4, -5

Table 20 provides the recent history of the Spartan-3AN speed files.

Table 20: **Spartan-3AN Speed File Version History**

Version	ISE Release	Description
1.41	ISE 10.1.03	Updated for Spartan-3A family. No change to data for Spartan-3AN family.
1.40	ISE 10.1.02	Updated for Spartan-3A family. No change to data for Spartan-3AN family.
1.39	ISE 10.1	Updated for Spartan-3A family. No change to data for Spartan-3AN family.
1.38	ISE 9.2.03i	Updated to Production. No change to data.
1.37	ISE 9.2.01i	Updated pin-to-pin setup and hold times, TMDS output adjustment, multiplier setup/hold times, and block RAM clock width.
1.36	ISE 9.2i	Added -5 speed grade, updated to Advance.
1.34	ISE 9.1.03i	Updated pin-to-pin timing.
1.32	ISE 9.1.01i	Preview speed files for -4 speed grade.

Table 25: **Propagation Times for the IOB Input Path *(Cont'd)***

Symbol	Description	Conditions	DELAY_VALUE	Device	Speed Grade		Units
					-5	-4	
					Max	Max	
T_{IOPID}	The time it takes for data to travel from the Input pin to the I output with the input delay programmed	LVCMOS25[2]	15	XC3S200AN	5.43	6.24	ns
			16		5.75	6.59	ns
			1	XC3S400AN	1.32	1.43	ns
			2		1.67	1.83	ns
			3		1.90	2.07	ns
			4		2.33	2.52	ns
			5		2.60	2.91	ns
			6		2.94	3.20	ns
			7		3.23	3.51	ns
			8		3.50	3.85	ns
			9		3.18	3.55	ns
			10		3.53	3.95	ns
			11		3.76	4.20	ns
			12		4.26	4.67	ns
			13		4.51	4.97	ns
			14		4.85	5.32	ns
			15		5.14	5.64	ns
			16		5.40	5.95	ns
			1	XC3S700AN	1.84	1.87	ns
			2		2.20	2.27	ns
			3		2.46	2.60	ns
			4		2.93	3.15	ns
			5		3.21	3.45	ns
			6		3.54	3.80	ns
			7		3.86	4.16	ns
			8		4.13	4.48	ns
			9		3.82	4.19	ns
			10		4.17	4.58	ns
			11		4.43	4.89	ns
			12		4.95	5.49	ns
			13		5.22	5.83	ns
			14		5.57	6.21	ns
			15		5.89	6.55	ns
			16		6.16	6.89	ns
			1	XC3S1400AN	1.95	2.18	ns
			2		2.29	2.59	ns
			3		2.54	2.84	ns
			4		2.96	3.30	ns

Table 25: **Propagation Times for the IOB Input Path *(Cont'd)***

Symbol	Description	Conditions	DELAY_VALUE	Device	Speed Grade		Units
					-5	-4	
					Max	Max	
T_{IOPID}	The time it takes for data to travel from the Input pin to the I output with the input delay programmed	LVCMOS25(2)	5	XC3S1400AN	3.17	3.52	ns
			6		3.52	3.92	ns
			7		3.82	4.18	ns
			8		4.10	4.57	ns
			9		3.84	4.31	ns
			10		4.20	4.79	ns
			11		4.46	5.06	ns
			12		4.87	5.51	ns
			13		5.07	5.73	ns
			14		5.43	6.08	ns
			15		5.73	6.33	ns
			16		6.01	6.77	ns
T_{IOPLI}	The time it takes for data to travel from the Input pin through the IFF latch to the I output with no input delay programmed	LVCMOS25(2)	IFD_DELAY_VALUE=0	XC3S50AN	1.70	1.81	ns
				XC3S200AN	1.85	2.04	ns
				XC3S400AN	1.44	1.74	ns
				XC3S700AN	1.48	1.74	ns
				XC3S1400AN	1.50	1.97	ns

Input Timing Adjustments

Table 26: **Input Timing Adjustments by IOSTANDARD**

Convert Input Time from LVCMOS25 to the Following Signal Standard (IOSTANDARD)	Add the Adjustment Below		Units
	Speed Grade		
	-5	-4	
Single-Ended Standards			
LVTTL	0.62	0.62	ns
LVCMOS33	0.54	0.54	ns
LVCMOS25	0	0	ns
LVCMOS18	0.83	0.83	ns
LVCMOS15	0.60	0.60	ns
LVCMOS12	0.31	0.31	ns
PCI33_3	0.41	0.41	ns
PCI66_3	0.41	0.41	ns
HSTL_I	0.72	0.72	ns
HSTL_III	0.77	0.77	ns
HSTL_I_18	0.69	0.69	ns
HSTL_II_18	0.69	0.69	ns
HSTL_III_18	0.79	0.79	ns
SSTL18_I	0.71	0.71	ns
SSTL18_II	0.71	0.71	ns
SSTL2_I	0.68	0.68	ns
SSTL2_II	0.68	0.68	ns
SSTL3_I	0.78	0.78	ns
SSTL3_II	0.78	0.78	ns

Table 26: **Input Timing Adjustments by IOSTANDARD**

Convert Input Time from LVCMOS25 to the Following Signal Standard (IOSTANDARD)	Add the Adjustment Below		Units
	Speed Grade		
	-5	-4	
Differential Standards			
LVDS_25	0.76	0.76	ns
LVDS_33	0.79	0.79	ns
BLVDS_25	0.79	0.79	ns
MINI_LVDS_25	0.78	0.78	ns
MINI_LVDS_33	0.79	0.79	ns
LVPECL_25	0.78	0.78	ns
LVPECL_33	0.79	0.79	ns
RSDS_25	0.79	0.79	ns
RSDS_33	0.77	0.77	ns
TMDS_33	0.79	0.79	ns
PPDS_25	0.79	0.79	ns
PPDS_33	0.79	0.79	ns
DIFF_HSTL_I_18	0.74	0.74	ns
DIFF_HSTL_II_18	0.72	0.72	ns
DIFF_HSTL_III_18	1.05	1.05	ns
DIFF_HSTL_I	0.72	0.72	ns
DIFF_HSTL_III	1.05	1.05	ns
DIFF_SSTL18_I	0.71	0.71	ns
DIFF_SSTL18_II	0.71	0.71	ns
DIFF_SSTL2_I	0.74	0.74	ns
DIFF_SSTL2_II	0.75	0.75	ns
DIFF_SSTL3_I	1.06	1.06	ns
DIFF_SSTL3_II	1.06	1.06	ns

Notes:

1. The numbers in this table are tested using the methodology presented in Table 30 and are based on the operating conditions set forth in Table 10, Table 13, and Table 15.
2. These adjustments are used to convert input path times originally specified for the LVCMOS25 standard to times that correspond to other signal standards.

Output Propagation Times

Table 27: **Timing for the IOB Output Path**

Symbol	Description	Conditions	Device	Speed Grade		Units
				-5	-4	
				Max	Max	
Clock-to-Output Times						
T_{IOCKP}	When reading from the Output Flip-Flop (OFF), the time from the active transition at the OCLK input to data appearing at the Output pin	LVCMOS25(2), 12 mA output drive, Fast slew rate	All	2.87	3.13	ns
Propagation Times						
T_{IOOP}	The time it takes for data to travel from the IOB's O input to the Output pin	LVCMOS25(2), 12 mA output drive, Fast slew rate	All	2.78	2.91	ns
Set/Reset Times						
T_{IOSRP}	Time from asserting the OFF's SR input to setting/resetting data at the Output pin	LVCMOS25(2), 12 mA output drive, Fast slew rate	All	3.63	3.89	ns
T_{IOGSRQ}	Time from asserting the Global Set Reset (GSR) input on the STARTUP_SPARTAN3A primitive to setting/resetting data at the Output pin			8.62	9.65	ns

Notes:

1. The numbers in this table are tested using the methodology presented in Table 30 and are based on the operating conditions set forth in Table 10 and Table 13.
2. This time requires adjustment whenever a signal standard other than LVCMOS25 with 12 mA drive and Fast slew rate is assigned to the data Output. When this is true, *add* the appropriate Output adjustment from Table 29.

Table 32: **Recommended Number of Simultaneously Switching Outputs per V_{CCO}-GND Pair *(Cont'd)***

Signal Standard (IOSTANDARD)			Package Type			
			TQG144		FTG256, FGG400, FGG484, FGG676	
			Top, Bottom Banks 0,2	Left, Right Banks 1,3	Top, Bottom Banks 0,2	Left, Right Banks 1,3
LVCMOS25	Slow	2	16	16	76	76
		4	10	10	46	46
		6	8	8	33	33
		8	7	7	24	24
		12	6	6	18	18
		16	–	6	–	11
		24	–	5	–	7
	Fast	2	12	12	18	18
		4	10	10	14	14
		6	8	8	6	6
		8	6	6	6	6
		12	3	3	3	3
		16	–	3	–	3
		24	–	2	–	2
	QuietIO	2	36	36	76	76
		4	30	30	60	60
		6	24	24	48	48
		8	20	20	36	36
		12	12	12	36	36
		16	–	12	–	36
		24	–	8	–	8

Table 32: **Recommended Number of Simultaneously Switching Outputs per V_{CCO}-GND Pair *(Cont'd)***

Signal Standard (IOSTANDARD)			Package Type			
			TQG144		FTG256, FGG400, FGG484, FGG676	
			Top, Bottom Banks 0,2	Left, Right Banks 1,3	Top, Bottom Banks 0,2	Left, Right Banks 1,3
LVCMOS18	Slow	2	13	13	64	64
		4	8	8	34	34
		6	8	8	22	22
		8	7	7	18	18
		12	–	5	–	13
		16	–	5	–	10
	Fast	2	13	13	18	18
		4	8	8	9	9
		6	7	7	7	7
		8	4	4	4	4
		12	–	4	–	4
		16	–	3	–	3
	QuietIO	2	30	30	64	64
		4	24	24	64	64
		6	20	20	48	48
		8	16	16	36	36
		12	–	12	–	36
		16	–	12	–	24
LVCMOS15	Slow	2	12	12	55	55
		4	7	7	31	31
		6	7	7	18	18
		8	–	6	–	15
		12	–	5	–	10
	Fast	2	10	10	25	25
		4	7	7	10	10
		6	6	6	6	6
		8	–	4	–	4
		12	–	3	–	3
	QuietIO	2	30	30	70	70
		4	21	21	40	40
		6	18	18	31	31
		8	–	12	–	31
		12	–	12	–	20

Configurable Logic Block (CLB) Timing

Table 33: **CLB (SLICEM) Timing**

Symbol	Description	Speed Grade				Units
		-5		-4		
		Min	Max	Min	Max	
Clock-to-Output Times						
T_{CKO}	When reading from the FFX (FFY) Flip-Flop, the time from the active transition at the CLK input to data appearing at the XQ (YQ) output	–	0.60	–	0.68	ns
Setup Times						
T_{AS}	Time from the setup of data at the F or G input to the active transition at the CLK input of the CLB	0.18	–	0.36	–	ns
T_{DICK}	Time from the setup of data at the BX or BY input to the active transition at the CLK input of the CLB	1.58	–	1.88	–	ns
Hold Times						
T_{AH}	Time from the active transition at the CLK input to the point where data is last held at the F or G input	0	–	0	–	ns
T_{CKDI}	Time from the active transition at the CLK input to the point where data is last held at the BX or BY input	0	–	0	–	ns
Clock Timing						
T_{CH}	The High pulse width of the CLB's CLK signal	0.63	–	0.75	–	ns
T_{CL}	The Low pulse width of the CLK signal	0.63	–	0.75	–	ns
F_{TOG}	Toggle frequency (for export control)	0	770	0	667	MHz
Propagation Times						
T_{ILO}	The time it takes for data to travel from the CLB's F (G) input to the X (Y) output	–	0.62	–	0.71	ns
Set/Reset Pulse Width						
T_{RPW_CLB}	The minimum allowable pulse width, High or Low, to the CLB's SR input	1.33	–	1.61	–	ns

Notes:

1. The numbers in this table are based on the operating conditions set forth in Table 10.

18 x 18 Embedded Multiplier Timing

Table 37: **18 x 18 Embedded Multiplier Timing**

Symbol	Description	Speed Grade				Units
		-5		-4		
		Min	Max	Min	Max	
Combinatorial Delay						
T_{MULT}	Combinational multiplier propagation delay from the A and B inputs to the P outputs, assuming 18-bit inputs and a 36-bit product (AREG, BREG, and PREG registers unused)	–	4.36	–	4.88	ns
Clock-to-Output Times						
T_{MSCKP_P}	Clock-to-output delay from the active transition of the CLK input to valid data appearing on the P outputs when using the PREG register(2,3)	–	0.84	–	1.30	ns
T_{MSCKP_A} T_{MSCKP_B}	Clock-to-output delay from the active transition of the CLK input to valid data appearing on the P outputs when using either the AREG or BREG register(2,4)	–	4.44	–	4.97	ns
Setup Times						
T_{MSDCK_P}	Data setup time at the A or B input before the active transition at the CLK when using only the PREG output register (AREG, BREG registers unused)(3)	3.56	–	3.98	–	ns
T_{MSDCK_A}	Data setup time at the A input before the active transition at the CLK when using the AREG input register(4)	0.00	–	0.00	–	ns
T_{MSDCK_B}	Data setup time at the B input before the active transition at the CLK when using the BREG input register(4)	0.00	–	0.00	–	ns
Hold Times						
T_{MSCKD_P}	Data hold time at the A or B input after the active transition at the CLK when using only the PREG output register (AREG, BREG registers unused)(3)	0.00	–	0.00	–	ns
T_{MSCKD_A}	Data hold time at the A input after the active transition at the CLK when using the AREG input register(4)	0.35	–	0.45	–	ns
T_{MSCKD_B}	Data hold time at the B input after the active transition at the CLK when using the BREG input register(4)	0.35	–	0.45	–	ns
Clock Frequency						
F_{MULT}	Internal operating frequency for a two-stage 18x18 multiplier using the AREG and BREG input registers and the PREG output register(5)	0	280	0	250	MHz

Notes:

1. The numbers in this table are based on the operating conditions set forth in Table 10.
2. The PREG register is typically used in both single-stage and two-stage pipelined multiplier implementations.
3. The PREG register is typically used when inferring a single-stage multiplier.
4. Input registers AREG or BREG are typically used when inferring a two-stage multiplier.
5. Combinational delay is less and pipelined performance is higher when multiplying input data with less than 18 bits.

Digital Clock Manager (DCM) Timing

For specification purposes, the DCM consists of three key components: the Delay-Locked Loop (DLL), the Digital Frequency Synthesizer (DFS), and the Phase Shifter (PS).

Aspects of DLL operation play a role in all DCM applications. All such applications inevitably use the CLKIN and the CLKFB inputs connected to either the CLK0 or the CLK2X feedback, respectively. Thus, specifications in the DLL tables (Table 39 and Table 40) apply to any application that only employs the DLL component. When the DFS and/or the PS components are used together with the DLL, then the specifications listed in the DFS and PS tables (Table 41 through Table 44) supersede any corresponding ones in the DLL tables. DLL specifications that do not change with the addition of DFS or PS functions are presented in Table 39 and Table 40.

Period jitter and cycle-cycle jitter are two of many different ways of specifying clock jitter. Both specifications describe statistical variation from a mean value.

Period jitter is the worst-case deviation from the ideal clock period over a collection of millions of samples. In a histogram of period jitter, the mean value is the clock period.

Cycle-cycle jitter is the worst-case difference in clock period between adjacent clock cycles in the collection of clock periods sampled. In a histogram of cycle-cycle jitter, the mean value is zero.

Spread Spectrum

DCMs accept typical spread spectrum clocks as long as they meet the input requirements. The DLL will track the frequency changes created by the spread spectrum clock to drive the global clocks to the FPGA logic. See XAPP469: *Spread-Spectrum Clocking Reception for Displays* for details.

Delay-Locked Loop (DLL)

Table 39: **Recommended Operating Conditions for the DLL**

Symbol		Description		Speed Grade				Units
				-5		-4		
				Min	Max	Min	Max	
Input Frequency Ranges								
F_{CLKIN}	CLKIN_FREQ_DLL	Frequency of the CLKIN clock input		5(2)	280(3)	5(2)	250(3)	MHz
Input Pulse Requirements								
CLKIN_PULSE		CLKIN pulse width as a percentage of the CLKIN period	$F_{CLKIN} \le 150$ MHz	40%	60%	40%	60%	%
			$F_{CLKIN} > 150$ MHz	45%	55%	45%	55%	%
Input Clock Jitter Tolerance and Delay Path Variation(4)								
CLKIN_CYC_JITT_DLL_LF		Cycle-to-cycle jitter at the CLKIN input	$F_{CLKIN} \le 150$ MHz	–	±300	–	±300	ps
CLKIN_CYC_JITT_DLL_HF			$F_{CLKIN} > 150$ MHz	–	±150	–	±150	ps
CLKIN_PER_JITT_DLL		Period jitter at the CLKIN input		–	±1	–	±1	ns
CLKFB_DELAY_VAR_EXT		Allowable variation of off-chip feedback delay from the DCM output to the CLKFB input		–	±1	–	±1	ns

Notes:

1. DLL specifications apply when any of the DLL outputs (CLK0, CLK90, CLK180, CLK270, CLK2X, CLK2X180, or CLKDV) are in use.
2. The DFS, when operating independently of the DLL, supports lower FCLKIN frequencies. See Table 41.
3. The CLKIN_DIVIDE_BY_2 attribute can be used to increase the effective input frequency range up to F_{BUFG}. When set to TRUE, CLKIN_DIVIDE_BY_2 divides the incoming clock frequency by two as it enters the DCM.
4. CLKIN input jitter beyond these limits might cause the DCM to lose lock.
5. The DCM specifications are guaranteed when both adjacent DCMs are locked.

In-System Flash (ISF) Memory Timing

Table 48: **In-System Flash (ISF) Memory Operations**

Symbol	Description	Device	Typical	Max	Units
T_{XFER}	Page to Buffer transfer time	All	–	400	µs
T_{COMP}	Page to Buffer compare time	All	–	400	µs
T_{PP}	Page Programming time	XC3S50AN XC3S200AN XC3S400AN	2	4	ms
		XC3S700AN XC3S1400AN	3	6	ms
T_{PE}	Page Erase time	XC3S50AN XC3S200AN XC3S400AN	13	32	ms
		XC3S700AN XC3S1400AN	15	35	ms
T_{PEP}	Page Erase and Programming time	XC3S50AN XC3S200AN XC3S400AN XC3S700AN	14	35	ms
		XC3S1400AN	17	40	ms
T_{BE}	Block Erase time	XC3S50AN	15	35	ms
		XC3S200AN XC3S400AN	30	75	ms
		XC3S700AN XC3S1400AN	45	100	ms
T_{SE}	Sector Erase time	XC3S50AN	0.8	2.5	s
		XC3S200AN XC3S400AN XC3S700AN XC3S1400AN	1.6	5	s

Suspend Mode Timing

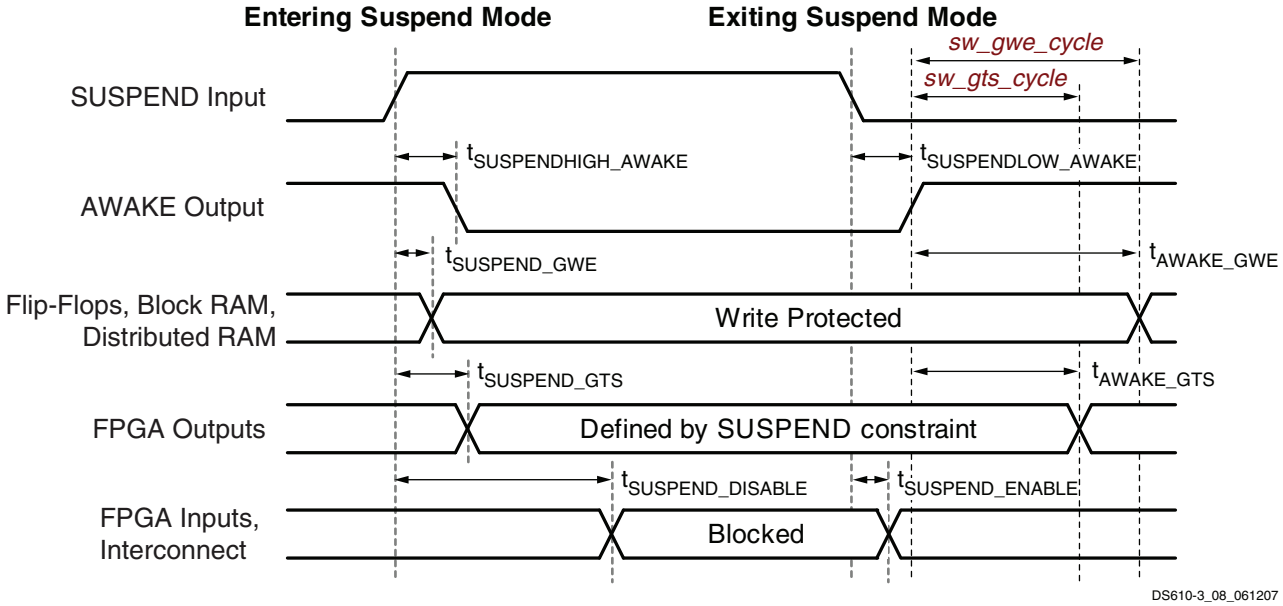

Figure 12: **Suspend Mode Timing**

Table 49: **Suspend Mode Timing Parameters**

Symbol	Description	Min	Typ	Max	Units
Entering Suspend Mode					
$T_{SUSPENDHIGH\_AWAKE}$	Rising edge of SUSPEND pin to falling edge of AWAKE pin without glitch filter (***suspend_filter:No***)	–	7	–	ns
$T_{SUSPENDFILTER}$	Adjustment to SUSPEND pin rising edge parameters when glitch filter enabled (***suspend_filter:Yes***)	+160	+300	+600	ns
$T_{SUSPEND\_GTS}$	Rising edge of SUSPEND pin until FPGA output pins drive their defined SUSPEND constraint behavior	–	10	–	ns
$T_{SUSPEND\_GWE}$	Rising edge of SUSPEND pin to write-protect lock on all writable clocked elements	–	< 5	–	ns
$T_{SUSPEND\_DISABLE}$	Rising edge of the SUSPEND pin to FPGA input pins and interconnect disabled	–	340	–	ns
Exiting Suspend Mode					
$T_{SUSPENDLOW\_AWAKE}$	Falling edge of the SUSPEND pin to rising edge of the AWAKE pin Does not include DCM lock time	–	4 to 108	–	µs
$T_{SUSPEND\_ENABLE}$	Falling edge of the SUSPEND pin to FPGA input pins and interconnect re-enabled	–	3.7 to 109	–	µs
T_{AWAKE_GWE1}	Rising edge of the AWAKE pin until write-protect lock released on all writable clocked elements, using ***sw_clk:InternalClock*** and ***sw_gwe_cycle:1***	–	67	–	ns
T_{AWAKE_GWE512}	Rising edge of the AWAKE pin until write-protect lock released on all writable clocked elements, using ***sw_clk:InternalClock*** and ***sw_gwe_cycle:512***	–	14	–	µs
T_{AWAKE_GTS1}	Rising edge of the AWAKE pin until outputs return to the behavior described in the FPGA application, using ***sw_clk:InternalClock*** and ***sw_gts_cycle:1***	–	57	–	ns
T_{AWAKE_GTS512}	Rising edge of the AWAKE pin until outputs return to the behavior described in the FPGA application, using ***sw_clk:InternalClock*** and ***sw_gts_cycle:512***	–	14	–	µs

Notes:

1. These parameters based on characterization.
2. For information on using the Spartan-3AN Suspend feature, see XAPP480: *Using Suspend Mode in Spartan-3 Generation FPGAs*.

Table 58: **Configuration Timing Requirements for Attached SPI Serial Flash**

Symbol	Description	Requirement	Units
T_{CCS}	SPI serial Flash PROM chip-select time	$T_{CCS} \leq T_{MCCL1} - T_{CCO}$	ns
T_{DSU}	SPI serial Flash PROM data input setup time	$T_{DSU} \leq T_{MCCL1} - T_{CCO}$	ns
T_{DH}	SPI serial Flash PROM data input hold time	$T_{DH} \leq T_{MCCH1}$	ns
T_V	SPI serial Flash PROM data clock-to-output time	$T_V \leq T_{MCCLn} - T_{DCC}$	ns
f_C or f_R	Maximum SPI serial Flash PROM clock frequency (also depends on specific read command used)	$f_C \geq \frac{1}{T_{CCLKn(min)}}$	MHz

Notes:

1. These requirements are for successful FPGA configuration in SPI mode, where the FPGA generates the CCLK signal. The post-configuration timing can be different to support the specific needs of the application loaded into the FPGA.
2. Subtract additional printed circuit board routing delay as required by the application.

Byte Peripheral Interface (BPI) Configuration Timing

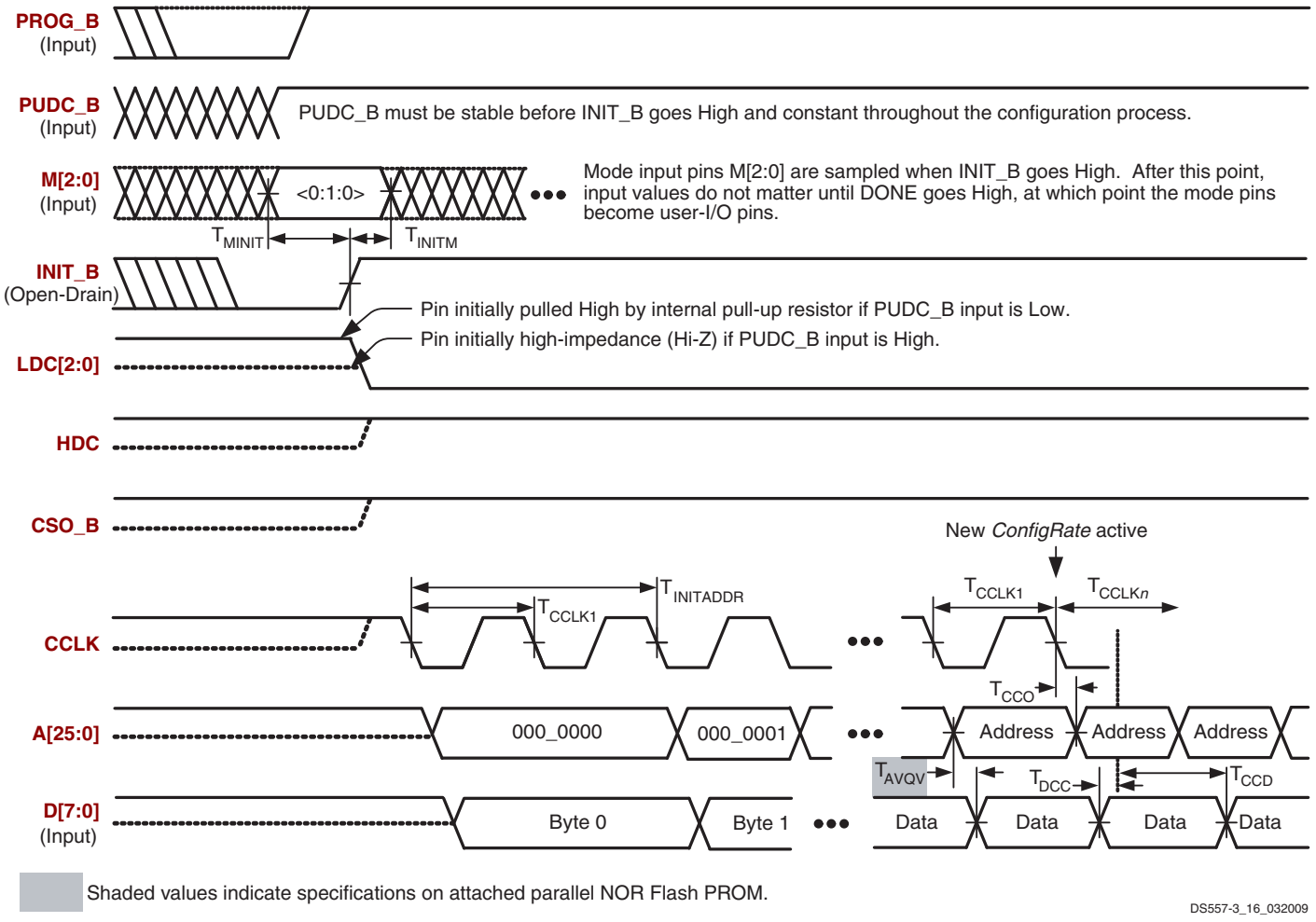

Figure 17: **Waveforms for Byte-wide Peripheral Interface (BPI) Configuration**

Table 82: **Spartan-3AN FGG676 Pinout *(Cont'd)***

Bank	Pin Name	FGG676 Ball	Type
GND	GND	T14	GND
GND	GND	T16	GND
GND	GND	T21	GND
GND	GND	T26	GND
GND	GND	U10	GND
GND	GND	U13	GND
GND	GND	U17	GND
GND	GND	V3	GND
GND	GND	W8	GND
GND	GND	W14	GND
GND	GND	W19	GND
GND	GND	W24	GND
VCCAUX	SUSPEND	V20	PWR MGMT
VCCAUX	DONE	AB21	CONFIG
VCCAUX	PROG_B	A2	CONFIG
VCCAUX	TCK	A25	JTAG
VCCAUX	TDI	G7	JTAG
VCCAUX	TDO	E23	JTAG
VCCAUX	TMS	D4	JTAG
VCCAUX	VCCAUX	AB5	VCCAUX
VCCAUX	VCCAUX	AB11	VCCAUX
VCCAUX	VCCAUX	AB22	VCCAUX
VCCAUX	VCCAUX	E5	VCCAUX
VCCAUX	VCCAUX	E16	VCCAUX
VCCAUX	VCCAUX	E22	VCCAUX
VCCAUX	VCCAUX	J18	VCCAUX
VCCAUX	VCCAUX	K13	VCCAUX
VCCAUX	VCCAUX	L5	VCCAUX
VCCAUX	VCCAUX	N10	VCCAUX
VCCAUX	VCCAUX	P17	VCCAUX
VCCAUX	VCCAUX	T22	VCCAUX
VCCAUX	VCCAUX	U14	VCCAUX
VCCAUX	VCCAUX	V9	VCCAUX
VCCINT	VCCINT	K15	VCCINT
VCCINT	VCCINT	L12	VCCINT
VCCINT	VCCINT	L14	VCCINT
VCCINT	VCCINT	L16	VCCINT
VCCINT	VCCINT	M11	VCCINT
VCCINT	VCCINT	M13	VCCINT
VCCINT	VCCINT	M15	VCCINT

Table 82: **Spartan-3AN FGG676 Pinout *(Cont'd)***

Bank	Pin Name	FGG676 Ball	Type
VCCINT	VCCINT	M17	VCCINT
VCCINT	VCCINT	N12	VCCINT
VCCINT	VCCINT	N13	VCCINT
VCCINT	VCCINT	N14	VCCINT
VCCINT	VCCINT	N16	VCCINT
VCCINT	VCCINT	P11	VCCINT
VCCINT	VCCINT	P13	VCCINT
VCCINT	VCCINT	P14	VCCINT
VCCINT	VCCINT	P15	VCCINT
VCCINT	VCCINT	R12	VCCINT
VCCINT	VCCINT	R14	VCCINT
VCCINT	VCCINT	R16	VCCINT
VCCINT	VCCINT	T11	VCCINT
VCCINT	VCCINT	T13	VCCINT
VCCINT	VCCINT	T15	VCCINT
VCCINT	VCCINT	U12	VCCINT

User I/Os by Bank

Table 83 indicates how the 502 available user-I/O pins are distributed between the four I/O banks on the FGG676 package. The AWAKE pin is counted as a dual-purpose I/O.

Table 83: **User I/Os Per Bank for the XC3S1400AN in the FGG676 Package**

Package Edge	I/O Bank	Maximum I/Os	All Possible I/O Pins by Type				
			I/O	INPUT	DUAL	VREF	CLK
Top	0	120	82	20	1	9	8
Right	1	130	67	15	30	10	8
Bottom	2	120	67	14	21	10	8
Left	3	132	97	18	0	9	8
Total		**502**	**313**	**67**	**52**	**38**	**32**

Footprint Migration Differences

The XC3S1400AN is the only Spartan-3AN FPGA offered in the FGG676 package. The XC3S1400AN FPGA is pin compatible with the Spartan-3A XC3S1400A FPGA in the FG(G)676 package, although the Spartan-3A FPGA requires an external configuration source.

Right Half of FGG676 Package (Top View)

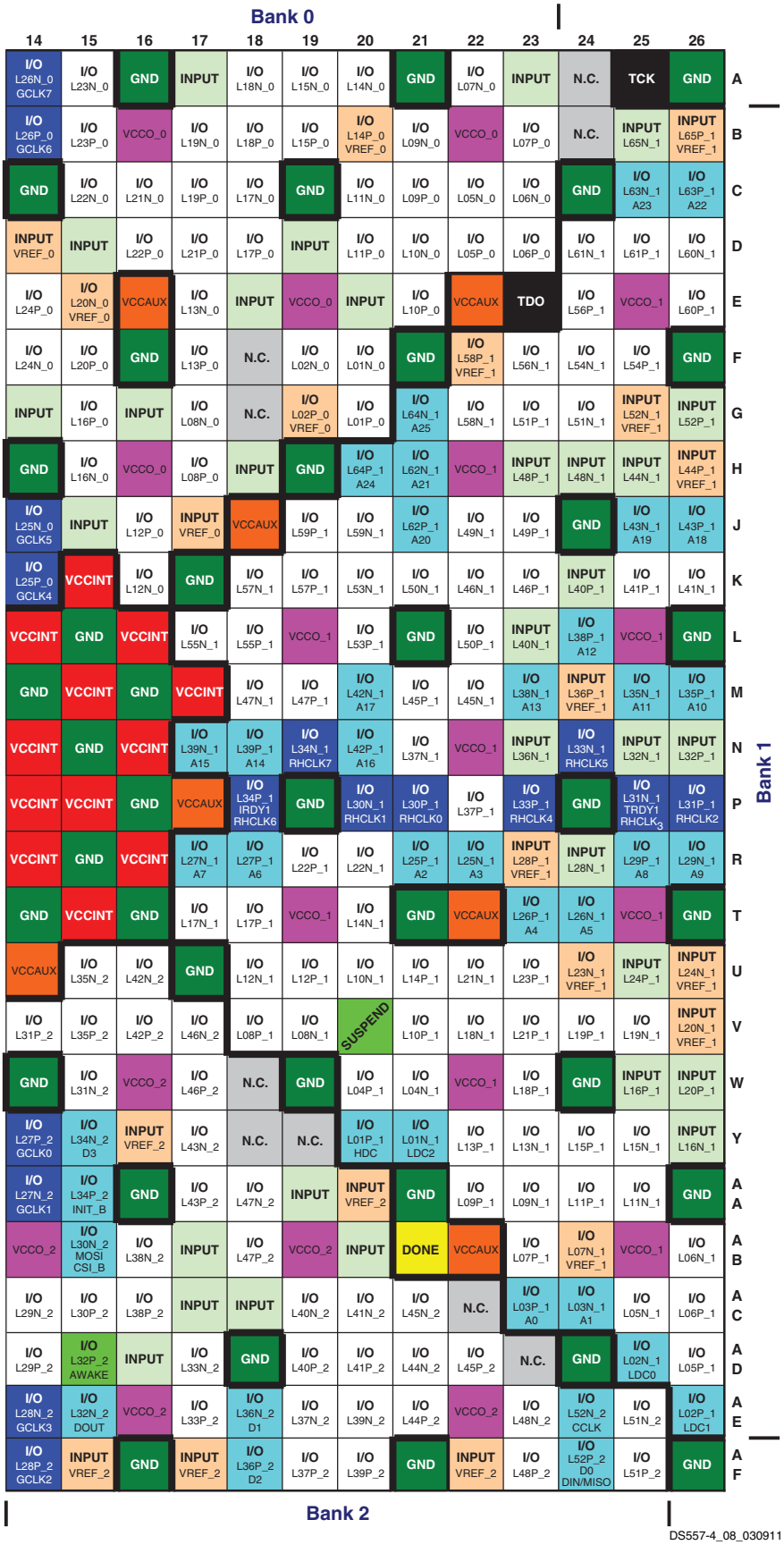

Figure 24: **FGG676 Package Footprint (Top View)**